

**Search Notes**

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Examiner

José R. Díaz

Applicant(s)/Patent under  
Reexamination

YUN ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	522, e23.013	2/6/2006	JRD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR